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FAIRCHILD SEMICONDUCTOR®

December 2001

FDG330P

P-Channel 1.8V Specified PowerTrench® MOSFET

General Description

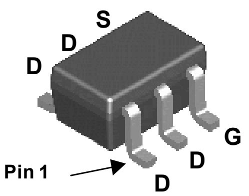
This P-Channel 1.8V specified MOSFET uses Fairchild's advanced low voltage PowerTrench process. It has been optimized for battery power management applications.

Applications

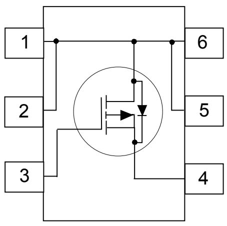
- Battery management
- Load switch

Features

- –2 A, –12 V. $R_{DS(ON)}$ = 110 mΩ @ V_{GS} = –4.5 V
  $R_{DS(ON)}$ = 150 mΩ @ V_{GS} = –2.5 V
  $R_{DS(ON)}$ = 215 mΩ @ V_{GS} = –1.8 V
- Low gate charge
- High performance trench technology for extremely low $R_{DS(ON)}$
- Compact industry standard SC70-6 surface mount package



SC70-6



Absolute Maximum Ratings

T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V_{DSS}	Drain-Source Voltage		–12	V
V_{GSS}	Gate-Source Voltage		± 8	V
I_D	Drain Current – Continuous	(Note 1a)	–2	A
	– Pulsed		–6	
P_D	Power Dissipation for Single Operation	(Note 1a)	0.75	W
		(Note 1b)	0.48	
T_J, T_{STG}	Operating and Storage Junction Temperature Range		–55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	Note 1b)	260	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
.30	FDG330P	7''	8mm	3000 units

Electrical Characteristics

T_A = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain–Source Breakdown Voltage	V_{GS} = 0 V, I_D = –250 µA	–12			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = –250 µA, Referenced to 25°C		–2.7		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = –10 V, V_{GS} = 0 V			–1	µA
I_{GSSF}	Gate–Body Leakage, Forward	V_{GS} = 8 V, V_{DS} = 0 V			100	nA
I_{GSSR}	Gate–Body Leakage, Reverse	V_{GS} = –8 V, V_{DS} = 0 V			–100	nA
On Characteristics (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS} = V_{GS}, I_D = –250 µA	–0.4	–0.7	–1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I_D = –250 µA, Referenced to 25°C		2.3		mV/°C
$R_{DS(on)}$	Static Drain–Source On–Resistance	V_{GS} = –4.5 V, I_D = –2.0 A V_{GS} = –2.5 V, I_D = –1.7 A V_{GS} = –1.8 V, I_D = –1.4 A V_{GS} = –4.5 V, I_D = –2.0 A, T_J = 125°C		84 107 145 98	110 150 215 148	mΩ
$I_{D(on)}$	On–State Drain Current	V_{GS} = –4.5 V, V_{DS} = –5 V	–6			A
g_{FS}	Forward Transconductance	V_{DS} = –5 V, I_D = –2.0 A		6.8		S
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS} = –6.0 V, V_{GS} = 0 V, f = 1.0 MHz		477		pF
C_{oss}	Output Capacitance			186		pF
C_{rss}	Reverse Transfer Capacitance			124		pF
Switching Characteristics (Note 2)						
$t_{d(on)}$	Turn–On Delay Time	V_{DD} = –6.0 V, I_D = 1 A, V_{GS} = –4.5 V, R_{GEN} = 6 Ω		10	20	ns
t_r	Turn–On Rise Time			11	20	ns
$t_{d(off)}$	Turn–Off Delay Time			12	22	ns
t_f	Turn–Off Fall Time			18	32	ns
Q_g	Total Gate Charge	V_{DS} = –6.0 V, I_D = –2.0 A, V_{GS} = –4.5 V		5	7	nC
Q_{gs}	Gate–Source Charge			0.8		nC
Q_{gd}	Gate–Drain Charge			1.4		nC
Drain–Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain–Source Diode Forward Current				–0.62	A
V_{SD}	Drain–Source Diode Forward Voltage	V_{GS} = 0 V, I_S = –0.62 A (Note 2)		–0.7	–1.2	V

Notes:

1. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.

a.) 170°C/W when mounted on a 1 in^2 pad of 2 oz. copper.

b.) 260°C/W when mounted on a minimum pad.

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

Typical Characteristics

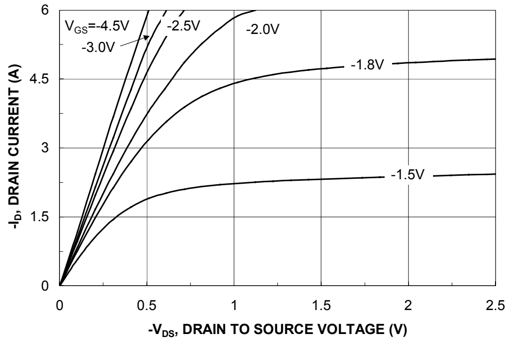


Figure 1. On-Region Characteristics.

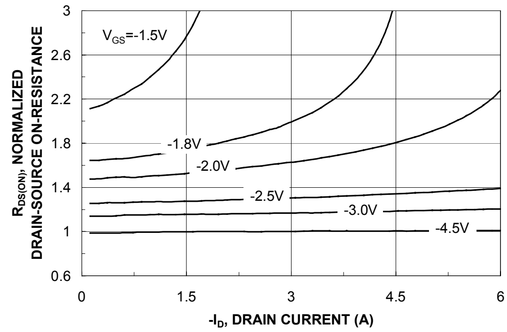


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

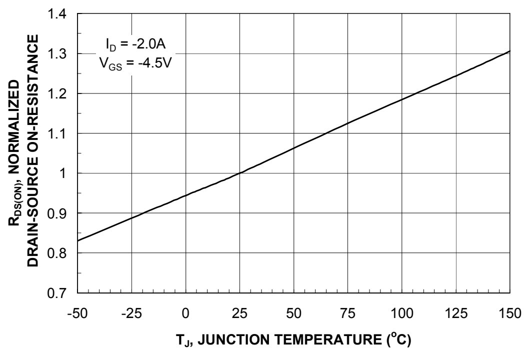


Figure 3. On-Resistance Variation with Temperature.

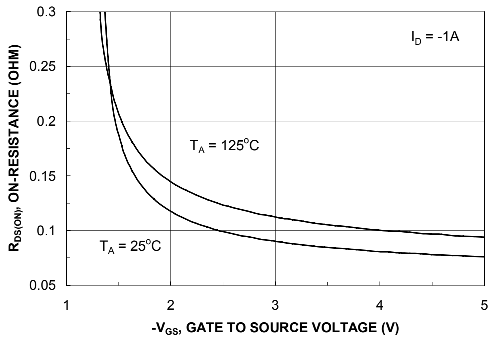


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

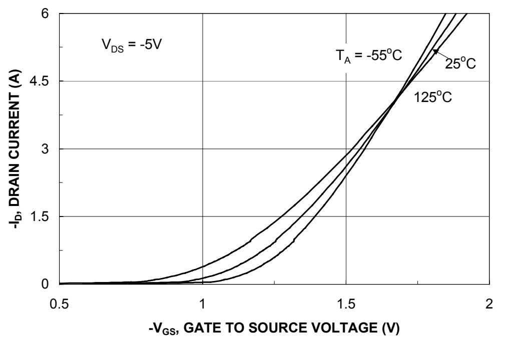


Figure 5. Transfer Characteristics.

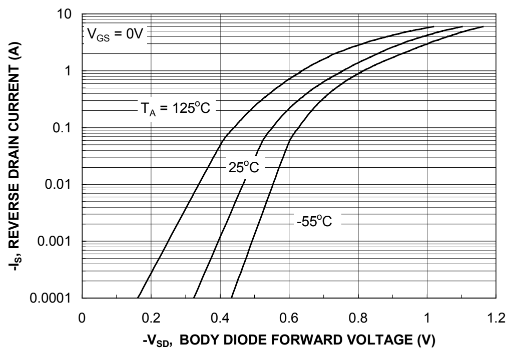


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics

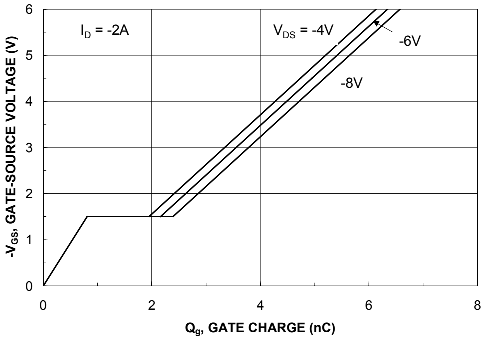


Figure 7. Gate Charge Characteristics.

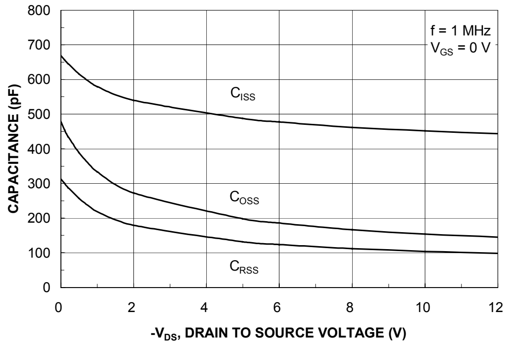


Figure 8. Capacitance Characteristics.

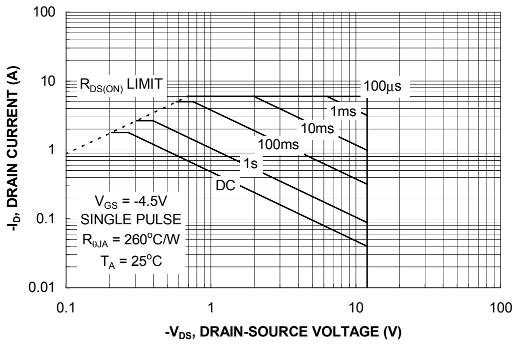


Figure 9. Maximum Safe Operating Area.

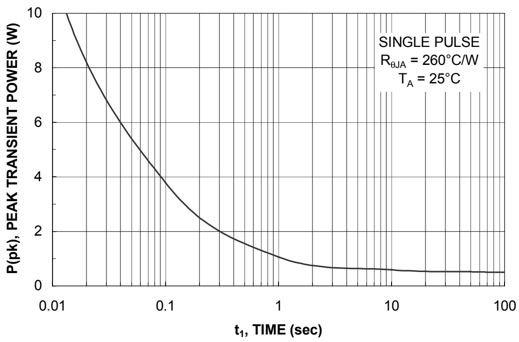


Figure 10. Single Pulse Maximum Power Dissipation.

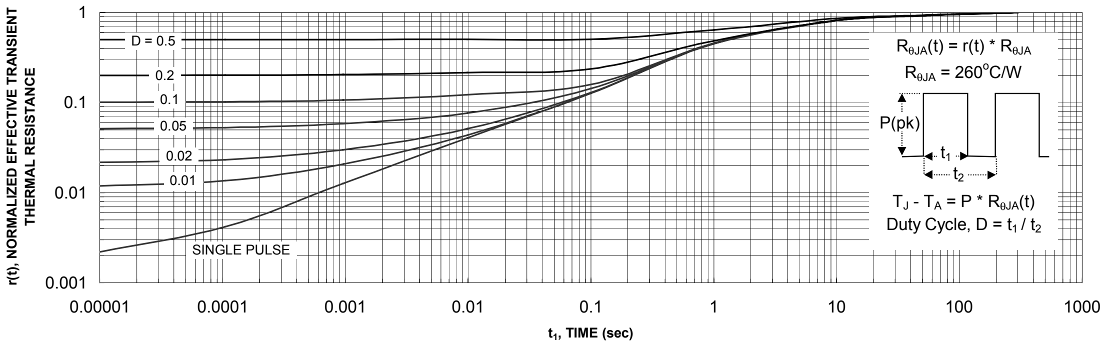


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b.
Transient thermal response will change depending on the circuit board design.

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